Reexamination 10/620,822 MA ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1

Application/Control No.

2874 Akm Enayet Ullah

Applicant(s)/Patent Under

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2002/0097962	07-2002	Yoshimura et al.	385/50
	B [']	US-2002/0039464	04-2002	Yoshimura et al.	385/14
	С	US-2002/0036055	03-2002	Yoshimura et al.	156/234
	D	US-2002/0028045	03-2002	Yoshimura et al.	385/50
	E	US-6,803,171	10-2004	Gronbeck et al.	430/270.1
	F	US-6,785,447	08-2004	Yoshimura et al.	385/42
	G	US-6,741,781	05-2004	Furuyama, Hideto	385/129
	Н	US-6,706,546	03-2004	Yoshimura et al.	438/31
	ı	US-6,690,845	02-2004	Yoshimura et al.	385/14
	J	US-6,684,007	01-2004	Yoshimura et al.	385/31
	К	US-6,669,801	12-2003	Yoshimura et al.	156/230
	L	US-6,611,635	08-2003	Yoshimura et al.	385/14
	М	US-6,343,171	01-2002	Yoshimura et al.	385/50

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
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	s					
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NON-PATENT DOCUMENTS

*	·	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	×	·

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.